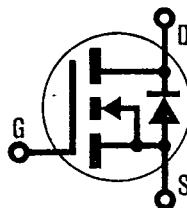




HEXFET® TRANSISTORS IRFH150

N-CHANNEL POWER MOSFETs



100 Volt, 0.06 Ohm HEXFET

The HEXFET® technology is the key to International Rectifier's advanced line of power MOSFET transistors. The efficient geometry and unique processing of the HEXFET design achieve very low on-state resistance combined with high transconductance and great device ruggedness.

The HEXFET transistors also feature all of the well established advantages of MOSFETs such as voltage control, very fast switching, ease of paralleling, and temperature stability of the electrical parameters.

They are well suited for applications such as switching power supplies, motor controls, inverters, choppers, audio amplifiers, and high energy pulse circuits.

Features:

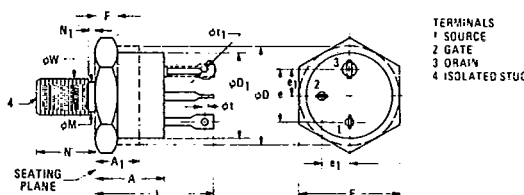
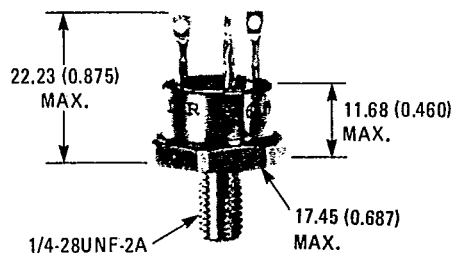
- Fast Switching
- Low Drive Current
- Ease of Paralleling
- Excellent Temperature Stability

Product Summary

Part Number	V _{DS}	R _{DS(on)}	I _D
IRFH150	100V	0.06Ω	30A*

*Current limited by pin diameter

CASE STYLE AND DIMENSIONS



TERMINALS
1 SOURCE
2 GATE
3 DRAIN
4 ISOLATED STUD

Symbol	Inches Min	Inches Max	Millimeters Min	Millimeters Max	Notes	Symbol	Inches Min	Inches Max	Millimeters Min	Millimeters Max	Notes
A	0.325	0.460	8.26	11.68		J	0.640	0.875	16.26	22.23	
A1	0.270	0.270	6.86	6.86	2	OM	0.220	0.249	5.59	6.32	
OD	0.610	0.687	15.49	17.45	2	N	0.422	0.455	10.72	11.56	
OD1	0.570	0.610	14.48	15.49		N1	0.090	0.090	2.29	2.29	
E	0.667	0.687	16.94	17.45		OL	0.055	0.072	1.39	1.83	
e	0.340	0.415	8.64	10.54	5	OL1	0.046	0.077	1.17	1.96	4
e1	0.170	0.213	4.32	5.41	5	OW	0.2225	0.2268	5.561	5.761	1
F	0.090	0.150	2.29	3.81	1						

NOTES
1. DIMENSION DOES NOT INCLUDE SEALING FLANGES.
2. PACKAGE CONTOUR OPTIONAL WITHIN DIMENSIONS SPECIFIED.
3. PITCH DIAMETER - THREAD 1/4-28 UNF-2A (COATED).
REFERENCE ISCREW THREAD STANDARDS FOR FEDERAL SERVICES - HANDBOOK H 28.
4. THIS TERMINAL CAN BE FLATTENED AND PIERCED OR NOOK TYPE.
5. POSITION OF LEADS IN RELATION TO THE HEXAGON IS NOT CONTROLLED.

Conforms to JEDEC Outline TO-210AC (TO-61)
Dimensions in Millimeters and (Inches)

Absolute Maximum Ratings

T-39-13

Parameter	IRFH150	Units
V_{DS} Drain - Source Voltage ①	100	V
V_{DGR} Drain - Gate Voltage ($R_{GS} = 20\text{ k}\Omega$) ①	100	V
$I_D @ T_C = 25^\circ\text{C}$ Continuous Drain Current	30*	A
$I_D @ T_C = 100^\circ\text{C}$ Continuous Drain Current	24	A
I_{DM} Pulsed Drain Current ③	120	A
V_{GS} Gate - Source Voltage	± 20	V
$P_D @ T_C = 25^\circ\text{C}$ Max. Power Dissipation	150 (See Fig. 13)	W
Linear Derating Factor	1.2 (See Fig. 13)	W/K ④
I_{LM} Inductive Current, Clamped (See Fig. 14 and 15) $L = 100\mu\text{H}$	120	A
T_J Operating Junction and T_{stg} Storage Temperature Range	-55 to 150	$^\circ\text{C}$
Lead Temperature	300 (0.063 in. (1.6mm) from case for 10s)	$^\circ\text{C}$

Electrical Characteristics @ $T_C = 25^\circ\text{C}$ (Unless Otherwise Specified)

Parameter	Type	Min.	Typ.	Max.	Units	Test Conditions
BV_{DSS} Drain - Source Breakdown Voltage	IRFH150	100	—	—	V	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$
$V_{GS(th)}$ Gate Threshold Voltage	IRFH150	2.0	—	4.0	V	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$
I_{GSS} Gate - Source Leakage Forward	IRFH150	—	—	100	nA	$V_{GS} = 20\text{V}$
I_{GSS} Gate - Source Leakage Reverse	IRFH150	—	—	-100	nA	$V_{GS} = -20\text{V}$
I_{DSS} Zero Gate Voltage Drain Current	IRFH150	—	—	250	μA	$V_{DS} = \text{Max. Rating}, V_{GS} = 0\text{V}$
	IRFH150	—	—	1000	μA	$V_{DS} = \text{Max. Rating} \times 0.8, V_{GS} = 0\text{V}, T_C = 125^\circ\text{C}$
$V_{DS(on)}$ On-State Voltage ②	IRFH150	—	—	1.80	V	$V_{GS} = 10\text{V}, I_D = 30\text{A}$
$R_{DS(on)}$ Static Drain-Source On-State Resistance ②	IRFH150	—	0.045	0.06	Ω	$V_{GS} = 10\text{V}, I_D = 24\text{A}$
g_{fs} Forward Transconductance ②	IRFH150	9.0	13	—	S (S)	$V_{DS} > I_{D(on)} \times R_{DS(on)}$ max., $I_D = 24\text{A}$
C_{iss} Input Capacitance	IRFH150	—	2000	3000	pF	$V_{GS} = 0\text{V}, V_{DS} = 25\text{V}, f = 1.0\text{ MHz}$ See Fig. 10
C_{oss} Output Capacitance	IRFH150	—	1000	1500	pF	
C_{rss} Reverse Transfer Capacitance	IRFH150	—	350	500	pF	
C_{dc} Drain-to-Case Capacitance	IRFH150	—	9.0	12	pF	$V_{DC} = 25\text{V}, f = 1\text{ MHz}$
$t_{d(on)}$ Turn-On Delay Time	IRFH150	—	—	35	ns	$V_{DD} = 25\text{V}, I_D = 24\text{A}, Z_\theta = 4.7^\circ\text{C/W}$ See Fig. 16 (MOSFET switching times are essentially independent of operating temperature.)
t_r Rise Time	IRFH150	—	—	100	ns	
$t_{d(off)}$ Turn-Off Delay Time	IRFH150	—	—	125	ns	
t_f Fall Time	IRFH150	—	—	100	ns	

Thermal Resistance

R_{thJC} Junction-to-Case	IRFH150	—	—	0.83	K/W ④	
R_{thCS} Case-to-Sink	IRFH150	—	0.4	—	K/W ④	Mounting surface flat, smooth, and greased.
R_{thJA} Junction-to-Ambient	IRFH150	—	—	40	K/W ④	Typical socket mount
T Mounting torque	Min.	2.26 (20)			N • m	Non-lubricated threads
	Max.	3.39 (30*)			(lbf • in.)	

Source-Drain Diode Ratings and Characteristics

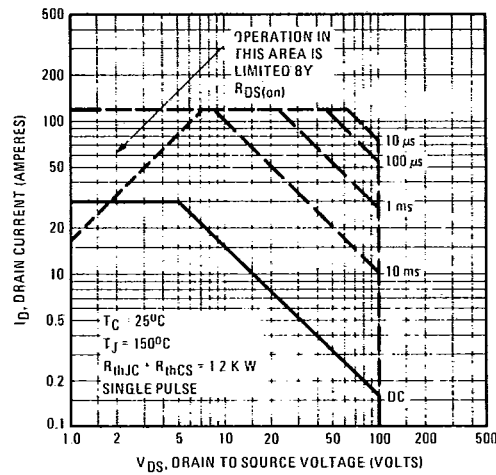
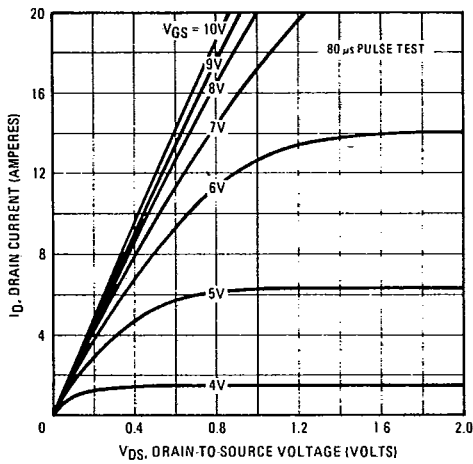
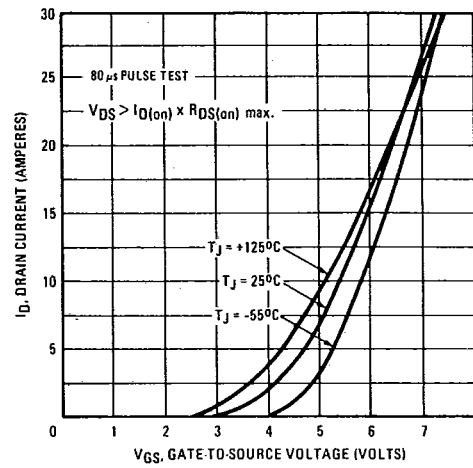
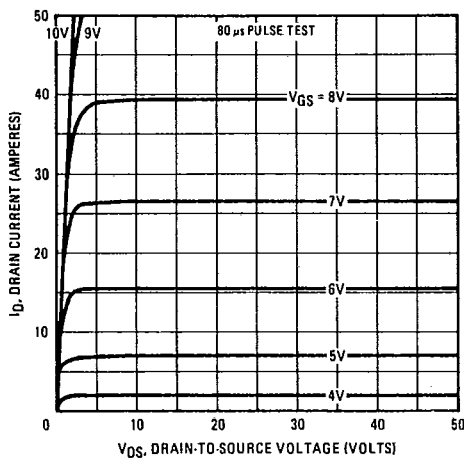
I_S Continuous Source Current (Body Diode)	IRFH150	—	—	30	A	Modified MOSFET symbol showing the integral reverse P-N junction rectifier.
I_{SM} Pulse Source Current (Body Diode) ③	IRFH150	—	—	120	A	
V_{SD} Diode Forward Voltage ②	IRFH150	—	—	1.9	V	$T_C = 25^\circ\text{C}, I_S = 30\text{A}, V_{GS} = 0\text{V}$
t_{rr} Reverse Recovery Time	IRFH150	—	600	—	ns	$T_J = 150^\circ\text{C}, I_F = 30\text{A}, dI_F/dt = 100\text{A}/\mu\text{s}$
Q_{RR} Reverse Recovered Charge	IRFH150	—	3.3	—	μC	$T_J = 150^\circ\text{C}, I_F = 30\text{A}, dI_F/dt = 100\text{A}/\mu\text{s}$
t_{on} Forward Turn-on Time	IRFH150	Intrinsic turn-on time is negligible. Turn-on speed is substantially controlled by $L_S + L_D$.				

① $T_J = 25^\circ\text{C}$ to 150°C . ② Pulse Test: Pulse width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$.

③ Repetitive Rating: Pulse width limited by max. junction temperature.

*Current limited by pin diameter. ④ $\text{K/W} = ^\circ\text{C/W}$
 $\text{W/K} = \text{W}/^\circ\text{C}$

See Transient Thermal Impedance Curve (Fig. 5).



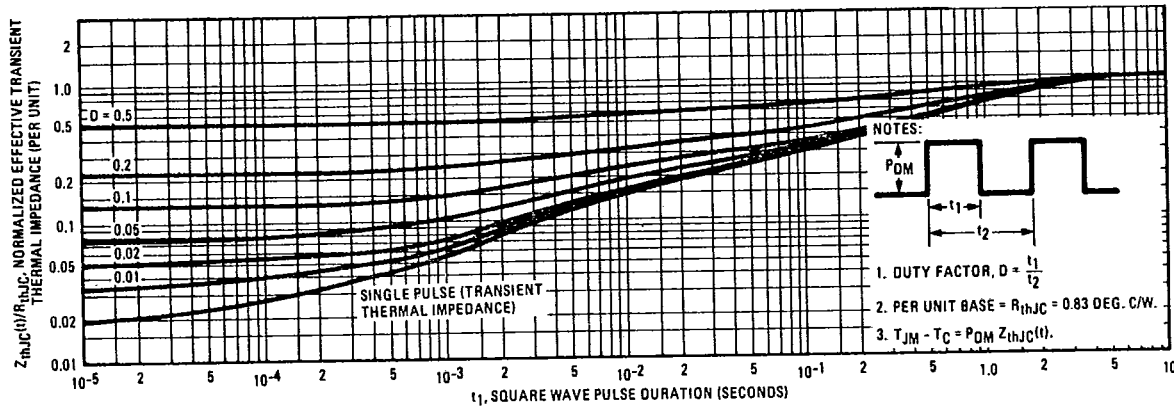


Fig. 5 - Maximum Effective Transient Thermal Impedance, Junction-to-Case Vs. Pulse Duration

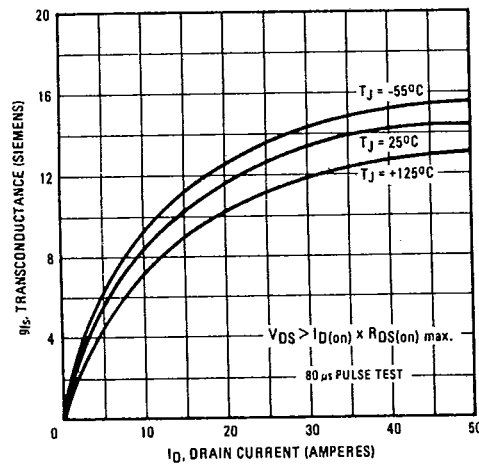


Fig. 6 - Typical Transconductance Vs. Drain Current

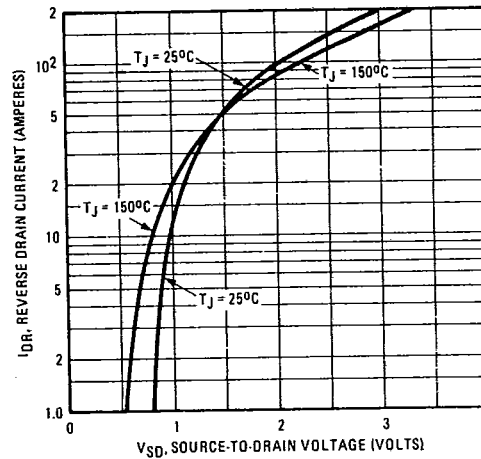


Fig. 7 - Typical Source-Drain Diode Forward Voltage

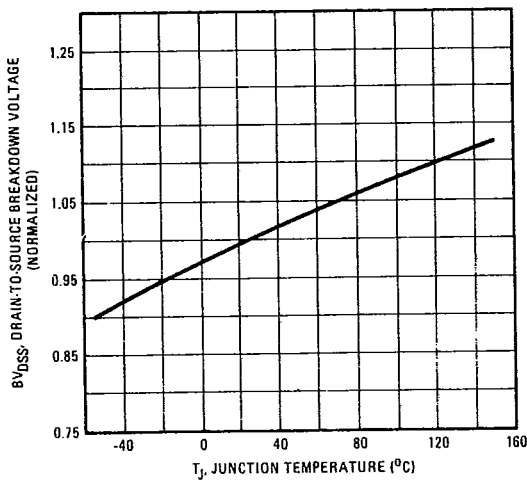


Fig. 8 - Breakdown Voltage Vs. Temperature

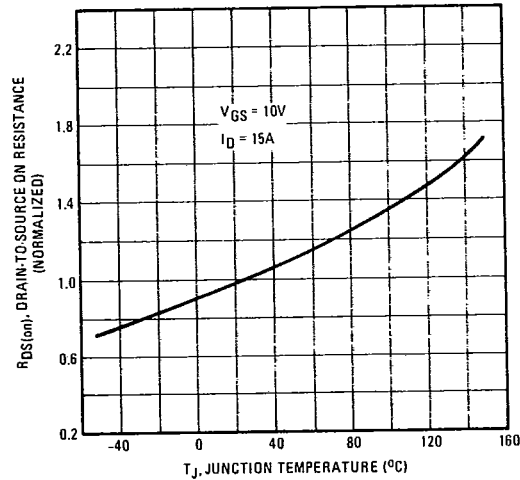


Fig. 9 - Normalized On-Resistance Vs. Temperature

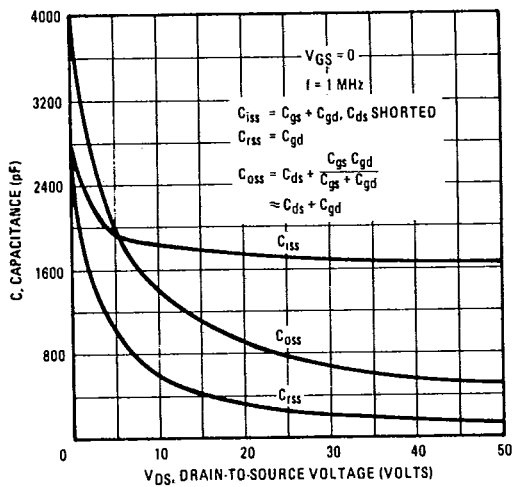


Fig. 10 - Typical Capacitance Vs. Drain-to-Source Voltage

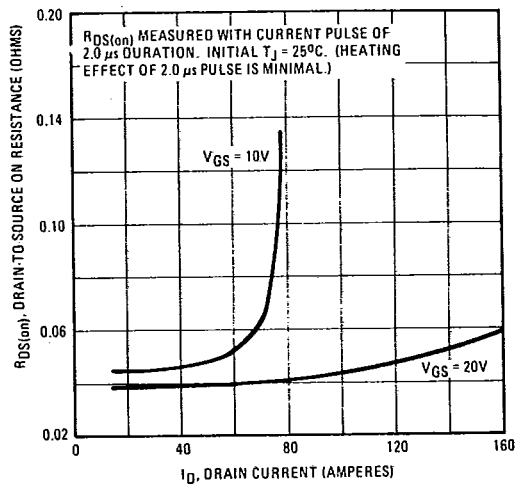


Fig. 11 - Typical On-Resistance Vs. Drain Current

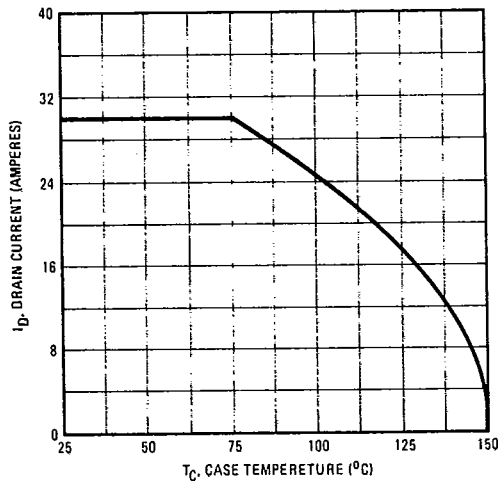


Fig. 12 - Maximum Drain Current Vs. Case Temperature

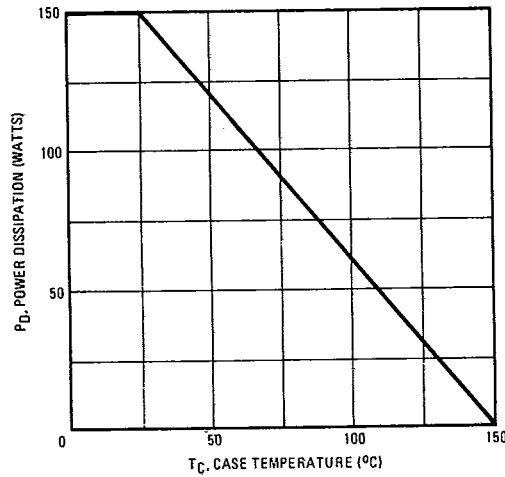


Fig. 13 - Power Vs. Temperature Derating Curve

T0-61

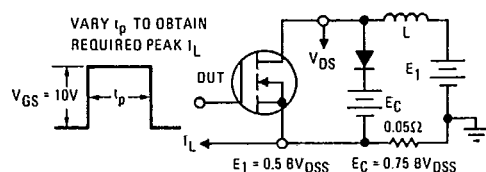


Fig. 14 - Clamped Inductive Test Circuit

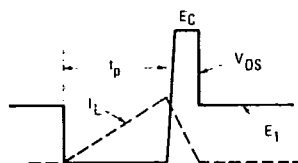


Fig. 15 - Clamped Inductive Waveforms

INTERNATIONAL RECTIFIER

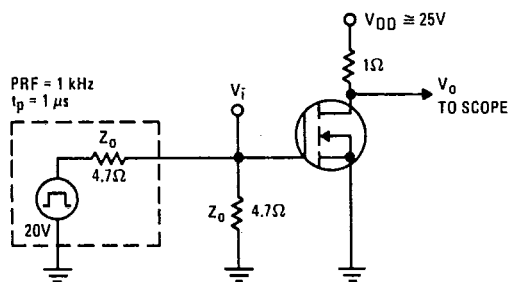


Fig. 16 - Switching Time Test Circuit